Unit in mm

TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE

2 S B 1 4 8 1

SWITCHING APPLICATIONS

• High DC Current Gain

: $h_{FE} = 2000$ (Min.) ($V_{CE} = -2V$, $I_{C} = -1.5A$)

• Low Saturation Voltage : $V_{CE (sat)} = -1.5V$ (Max.) ($I_{C} = -3A$)

• Complementary to 2SD2241

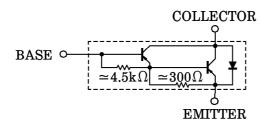
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Base Voltage		v_{CBO}	-100	V	
Collector-Emitter Voltage		v_{CEO}	-100	V	
Emitter-Base Voltage		$v_{ m EBO}$	-5	V	
Collector Current	DC	$I_{\mathbf{C}}$	±4	A	
	Pulse	I_{CP}	±6		
Base Current	$I_{\mathbf{B}}$	-0.3	A		
Collector Power	Ta=25°C	D.e.	2.0	W	
Dissipation	Tc = 25°C	$P_{\mathbf{C}}$	25		
Junction Temperature		$\mathrm{T_{j}}$	150	$^{\circ}\mathrm{C}$	
Storage Temperature Range		$\mathrm{T_{stg}}$	-55~150	°C	

1. BASE 2. COLLECTOR 3. EMITTER JEDEC EIAJ SC-67 TOSHIBA 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±0.2 2.7±

Weight: 1.7g

EQUIVALENT CIRCUIT

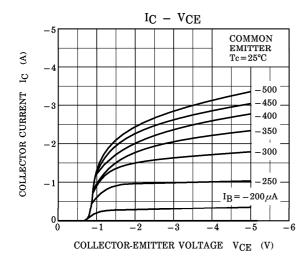


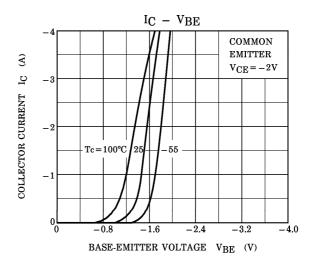
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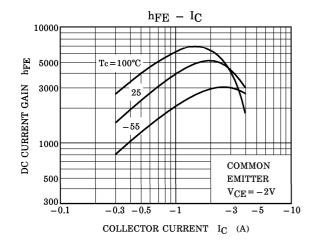
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

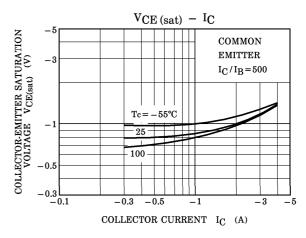
CHARAC	TERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Collector Cut-off Current		I_{CBO}	$V_{CB} = -100V, I_{E} = 0$	_	_	-2.0	μ A	
Emitter Cut-off Current		$I_{ m EBO}$	$V_{EB} = -5V, I_{C} = 0$	_	_	-2.5	mA	
Collector-Emitter Breakdown Voltage		V (BR) CEO	$I_{C} = -10 \text{mA}, I_{B} = 0$	-100	_	_	v	
DC Current Gain		hFE (1)	$V_{CE} = -2V, I_{C} = -1.5A$	2000	_	_		
		h _{FE} (2)	$V_{CE} = -2V, I_{C} = -3A$	1000	_	_	1	
Collector-Emitter Saturation Voltage		V _{CE} (sat)	$I_{C} = -3A, I_{B} = -6mA$	_	_	-1.5	V	
Base-Emitter Saturation Voltage		V _{BE} (sat)	$I_{C} = -3A, I_{B} = -6mA$	_	_	-2.0	v	
Collector-Emit Reverse Volta	ollector-Emitter $V_{\rm ECO}$ $I_{\rm C} = 1 {\rm A}, \ I_{\rm B} = 0$		_	_	2.0	v		
Switching Time	Turn-on Time	t _{on}	IB2 IB2 OUTPUT	_	0.15	_		
	Storage Time	t _{stg}	IB1 INPUT IB1	_	0.80	_	μ s	
	Fall Time	t_f	$-I_{B1} = I_{B2} = 6\text{mA} \qquad V_{CC} = -30V$ DUTY CYCLE \(\le 1\%\)	_	0.40	_		

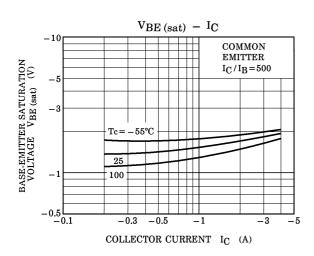
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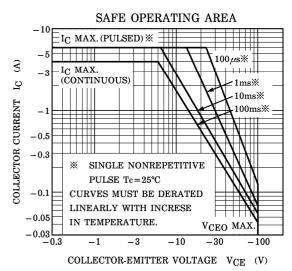












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